



Low Voltage, High Pin Count Burn-in and Test System

For burning-in and testing today's high pin count DUTs
such as *microprocessors, DSPs, and logic devices,*
which require low voltage



System Features

- Burns-in and tests high pin count devices
- Output Monitoring gives functional test results for every device during burn-in
- Device power supplied by 3 individual power supplies per BIB
- Production capacity with 32 BIB positions
- Engineering/QA configurations with up to 32 independent pattern zones
- Lot control and device protection

Signal and Bias Features

- 128 or 256 independent I/O channels
- Stimulus voltages as low as 0.5V
- Up to 24M pattern depth for BIST and JTAG applications
- 3 separate bias voltages per device

Software Features

- Windows 2000 operation and programming
- Modular test-plan development for ease of programming
- DUT pass/fail BIB map
- Easy interface to sorting BIB unloaders

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